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L16	l4 and load$3 near4 (address$4 or location$1 or point$3)	99	L16
L15	l4 and (store or load) near5 request$3	25	L15
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L13	l4 and l7	48	L13
L12	l4 and l6	13	L12
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L8	(711/201, 214)[CCLS]	275	L8

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L6	(712/23,206,207,219,230,245)![CCLS]	1884	L6
L5	(712/2-300)![CCLS]	10675	L5

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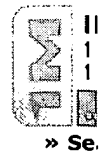| L4 | align$8 near12 (word$1 or byte$1 or 32 or thirty near1 two) near25 address$3 near8 (generat$3 or calculat$4 or comput$4) | 219 | L4 |
L3	L2 near15 (conflict$3 or contend$3 or contention$1 or collaps$5 or hazard$5 or dependen$5)	236	L3
L2	(store) near12 load near12 (order or sequenc$3)	2326	L2
L1	(command$3 or instruction$1 or micro near1 instruction$1) near 5 (fetch$6 or prefetch$6)	103749	L1

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1 **The microarchitecture of superscalar processors**
Smith, J.E.; Sohi, G.S.;
Proceedings of the IEEE , Volume: 83 , Issue: 12 , Dec. 1995
Pages:1609 - 1624

[Abstract]   [PDF Full-Text (1812 KB)]   **IEEE JNL**

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2 **A 330 MHz 4-way superscalar microprocessor**
Greenhill, D.; Anderson, E.; Bauman, J.; Charnas, A.; Cheerla, R.; Hao Chen; Doreswamy, M.; Ferolito, P.; Gopaladhine, S.; Ho, K.; Wenjay Hsu; Kongetira Melanson, R.; Reddy, V.; Salem, R.; Sathianathan, H.; Shah, S.; Shin, K.; Srivatsa, C.; Weisenbach, R.;
Solid-State Circuits Conference, 1997. Digest of Technical Papers. 44th ISSCC 1997 IEEE International , 6-8 Feb. 1997
Pages:166 - 167, 449

[Abstract]   [PDF Full-Text (1104 KB)]   **IEEE CNF**

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3 **A 7th-generation x86 microprocessor**
Hesley, S.; Andrade, V.; Burd, B.; Constant, G.; Correll, J.; Crowley, M.; Golo M.; Hopkins, N.; Islam, S.; Johnson, S.; Khondker, R.; Meyer, D.; Moench, J., Partovi, H.; Posey, R.; Weber, F.; Yong, J.;
Solid-State Circuits Conference, 1999. Digest of Technical Papers. ISSCC. 199 IEEE International , 15-17 Feb. 1999
Pages:92 - 93

[Abstract]   [PDF Full-Text (144 KB)]   **IEEE CNF**

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